Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	ar
10/824,184	MURAYAMA ET AL.	
Examiner	Art Unit	
Chuck Mah	3677	

	SEAR	CHED	
Class	Subclass	Date	Examiner
16	82		
	86A		
	86b		
	86c		
292	270	•	
•	769		
· · · · · ·	268		
201	266		
296	146,11	5 / 1	4
	146.1	7/240	-ap
	1 .		
	Updates	7/4/05	M
	Myl	1 3/20/	1 847.1

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
16	all		
	above	3 23 06	eym
		1 1	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Citation Backward Forward		
inventor Search	3/23/06	cym
		U
•		
		•
	·	
	ļ	